

PTO-1449 Information Disclosure Citation in an Application	Application No. <i>Unassigned</i>	Applicant(s): <i>STARIKOV ET AL.</i>
	Docket Number <i>065238.0128</i>	Group Art Unit <i>2814</i>

U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
W54 A	6,075,611	06/13/2000	DUSSAN V. ET AL.	356	432	05/07/1998
	B 6,034,404	03/07/2000	SOARES	257	415	12/05/1996
	C 5,955,972	09/21/1999	WADE	340	960	09/03/1997
	D 5,995,229	11/30/1999	OMI	356	374	09/22/1998
	E 5,990,500	11/23/1999	OKAZAKI	257	99	03/03/1999
	F 5,920,018	07/06/1999	WILKERSON, ET AL.	73	861.41	12/11/1996
	G 5,822,473	10/13/1998	MAGEL, ET AL.	385	12	02/28/1997
	H 5,591,963	01/07/1997	TAKEDA, ET AL.	250	214.1	08/08/1995
	I 5,442,169	08/15/1995	KUNZ	250	227.21	06/02/1993
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✓	N 4,900,373	02/13/1990	CHU, ET AL.	148	33.4	07/19/1989

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

NON-PATENT DOCUMENTS

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
W54 O	TEMPEZ, ET AL., "PHOTOENHANCED REACTIVE ION ETCHING OF III-V NITRIDES IN BCl ₃ /Cl ₂ /Ar/N ₂ PLASMAS," <i>J. Vac. Sci. Technol. A 17(4)</i> , JUL/AUG 1999, PG. 2209-2213	1999
P	MEDELCI, ET AL., "REACTIVE ION ETCHING OF BORON NITRIDE AND GALLIUM NITRIDE MATERIALS IN Cl ₂ /Ar AND BCl ₃ /Cl ₂ /Ar CHEMISTRIES," <i>MAT. RES. SOC. SYMP. PROC. VOL. 512</i> , PG. 285-291	1998
Q	STARIKOV, ET AL., "A HOT ELECTRONS-BASED WIDE SPECTRUM ON-ORBIT OPTICAL CALIBRATION SOURCE," <i>SPACE TECHNOLOGY AND APPLICATIONS INTERNATIONAL FORUM-1998</i> , PG. 648-653	1998
✓ R	STARIKOV, ET AL., "METAL-INSULATOR-SEMICONDUCTOR SCHOTTKY BARRIER STRUCTURES FABRICATED USING INTERFACIAL BN LAYERS GROWN ON GAN AND SiC FOR OPTOELECTRONIC DEVICE APPLICATIONS," <i>J. Vac. Sci. Technol. A 17(4)</i> , JUL/AUG 1999, PG. 1235-1238	1999

EXAMINER	DATE CONSIDERED
<i>J. P.</i>	<i>12/18/04</i>

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.